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## Patent Abstracts of Japan

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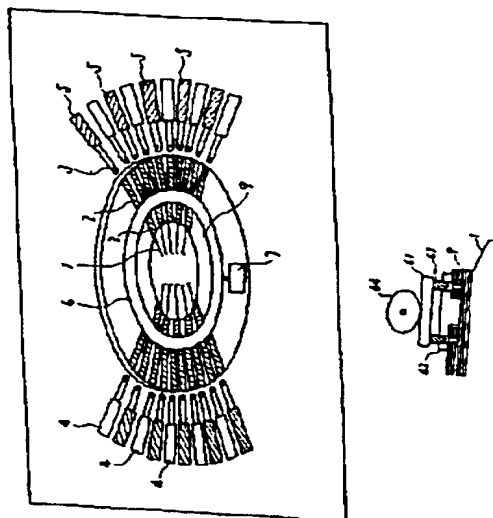
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APPLICANT : MITSUBISHI ELECTRIC CORP;

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TITLE : SEMICONDUCTOR TEST EQUIPMENT



ABSTRACT : PURPOSE: To make it possible to switch from a DC test circuit to a functional test circuit or vice versa using the simplest circuit possible by providing the equipment with a base ring to hold a probe and a rotatable ring which is installed between a socket of DUT and each test circuit and is rotated as the need arises.

CONSTITUTION: In the case that a DC test is conducted after terminals of a wafer-shaped DUT are brought into contact with probe styli 1, a ring 6 is rotated by a rotation device 7 after receipt of a command from an outside controller to connect a DC test circuit with the DUT terminals. If the ring 6 is rotated until the major axis of a cam 64 becomes horizontal, a presser ring 61 floats by the force of POGO pins 63 so the tips of the POGO pins 63 move into a connection ring 52. After that, the cam 64 is rotated 90 degrees to push the presser ring 61 and then to push out the POGO pins 63 to bring them into contact with the probe styli 1. When it comes to a functional test, the ring 6 is rotated in the same manner as above to connect the DUT with a functional test circuit 5 for performing the test.

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